Electronic Supplementary Material (ESI) for RSC Advances.
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Supplementary information

Overlayer deposition-induced control of oxide ion concentration in $SrFe_{0.5}Co_{0.5}O_{2.5}$ oxygen sponges

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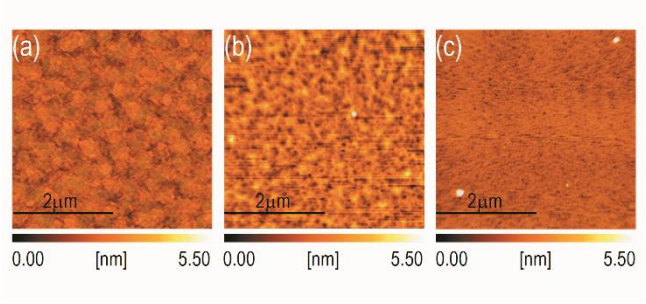

Fig S1. Topographic AFM images of (a) SFCO, (b) STO/SFCO, and (c) NSMO/SFCO films.

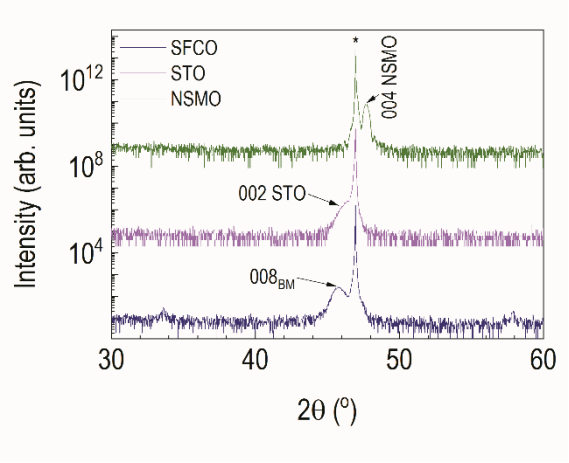

Fig S2. XRD patterns of SFCO (navy line), STO (magenta line) and NSMO (olive line).

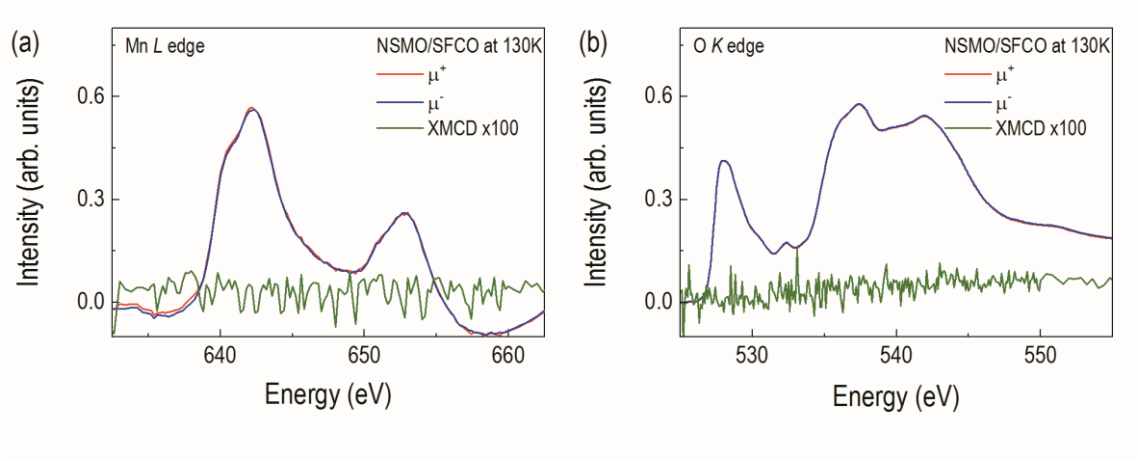

Fig S3. (a) Mn *L* edge and (b) O *K* edge XMCD spectra of an NSMO/SFCO. The XMCD spectra of Mn *L* edge and O *K* edge are multiplied 100 times, but there is no ferromagnetic signal.